

Non-destructive testing — Characteristics of focal spots in industrial X-ray systems for use in non-destructive testing —

Part 5: Measurement of the effective focal spot size of mini and micro focus X-ray tubes

The European Standard EN 12543-5:1999 has the status of a
British Standard

ICS 19.100

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National foreword

This British Standard is the English language version of EN 12543-5:1999. It supersedes BS 6932:1988 which is withdrawn.

The UK participation in its preparation was entrusted to Technical Committee WEE/46, Non-destructive testing, which has the responsibility to:

- aid enquirers to understand the text;
- present to the responsible European committee any enquiries on the interpretation, or proposals for change, and keep the UK interests informed;
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Summary of pages

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